

Electrical specifications

Frequency Range	2 – 18	[GHz]
VSWR (max.)	–	–
S₁₁ (max.)	≤ –10	[dB]
Impedance	50	[Ω]
Connector	SMA	–
Power (CW)	–	[W]
Power (Impulse)	–	[W]
Gain	–	[dBi]
Polarization	Linear – Dual	–

Physical specifications

W x L x H	620 x 620 x 500	[mm ³]
Weight	–	[g]



Features

Elliptika's Reflectometry arch is a compact, lightweight and lowcost setup to characterize objects such as radar absorbing materials.

Measurement do not need to take place in an anechoic chamber thanks to the absorbing material base and the polyurethane electromagnetically transparent structure.

Elliptika's Reflectometry arch is comprised of two dual polarization 2-18 GHz antennas placed at a 20° angle. The dual polarization antennas allow the user to measure both TE and TM polarization with no complex setup modifications. Moreover, the dual polarization allows the measurement of the cross polarization and of a circularly polarized incident wave with the use of a coupler (not included).

Specifications:

- Frequency range: 2 to 18 GHz
- 20° angle
- Polarization: TE, TM (included), LHCP or RHCP (optional)
- Cross-polarization
- No anechoic chamber required
- Compact and lightweight